PCN Number:		20131203000A			F	PCN Date: May 23, 2018				
Title: Conversion to Cu bo				nd wire						
Customer Contact:		PCN Manager Dep		nager	Dept:	Quali	ity	y Services		
Chang	Change Type:									
Assembly Site		Assembly Process		$\triangleright$	3	Assembly Materials				
Design				Electrical Specification				Mechanical Specification		
Test Site			<u> </u>	Packing/Shipping/Labeling				Test Process		
Wafer Bump Site			<u> </u>	Wafer Bump Material				Wafer Bun		
Wafer Fab Site			<u> </u>	Wafer Fab Materials				Wafer Fab Process		
		Part number change								
PCN Details										
	<b>Description of Change:</b> Revision A is to remove select devices in the Product Affected Section (with strikethrough) and						rikothrough) and			
					inadvertently add					
inging	gilled in yenow. I	iies	e ut	evices were	mauvertently aut		lu	not anected	a by this change.	
Texas Instruments is pleased to announce the qualification of Cu as a bond wire option for the selected devices shown below. All listed devices will remain in current assembly facility and there will be no other BOM changes.										
Reaso	Reason for Change:									
Continuity of supply.										
	1) To align with world technology trends and use wiring with enhanced mechanical and									
-	electrical properties									
<ol> <li>Maximize flexibility within our Assembly/Test production sites.</li> <li>Cu is easier to obtain and stock</li> </ol>										
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):										
None										
Changes to product identification resulting from this PCN:										
None										
Product Affected										
TRF3	705IRGER	ŦF	RF37	05IRGET	TRF37T05IF	RGER		TRF371	105IRGET	
Qualification Data										

Qualification Data				
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.				
Qual Vehicle: TRF37T05IRGE (MSL 2-260C)				
Package Construction Details				
Assembly Site:	Clark-AT	Mold Compound:	4208625	
# Pins-Designator, Family:	24-RGE, QFN	Mount Compound:	4207768	
Lead Finish	NiPdAuAg	Bond Wire:	0.80Mil Cu	

Qualification: 🗌 Plan 🛛	Test Results		
Reliability Test	Conditions	Sample Size / Fail	
Electrical Characterization	Side by Side (Au vs. Cu)	Pass	
ESD CDM	+/- 250V, 500V	3/0	
ESD HBM	+/- 500V, 1000V, 1500V	3/0	
Latch-up	(per JESD78)	6/0	

Reference Qualification Data						
This qualification has been developed for the validation of this change. The qualification data						
validates that the proposed change meets the applicable released technical specifications.						
Qual Vehicle: CDC750RGC (MSL 3-260C)						
Package Construction Details						
Assembly Site:	Clark AT Mold Compound:		4208625			
# Pins-Designator, Family:	64-RGC, QFN	-RGC, QFN Mount Compound:		4207768		
Lead Finish	NiPdAu Bond Wire:		0.8mil	0.8mil Cu/0.8mil Au		
Qualification: 🗌 Plan 🛛 Test Results						
Deliebility Teet	Canditiana	Canditiana		Sample Size/Fail		
Reliability Test	Conditions		Lot#1	Lot#2	Lot#3	
**High Temp. Storage Bake	170C (420 hrs)		77/0	77/0	77/0	
**Biased HAST	130C/85%RH (96 Hrs)		77/0	77/0	77/0	
**Autoclave	121C, 2 atm (96 Hrs)		77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (500 Cyc)		77/0	77/0	77/0	
Ball Bond Shear	76 balls, 3 units min		Pass	Pass	Pass	
Bond Pad Cratering Check				Pass	Pass	
Bond Pull	76 Wire, 3 unit	Pass	Pass	Pass		
Notes **- Preconditioning sequence: Level 3-260C.						

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com